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(54) **LOW LEAKAGE AND DATA RETENTION CIRCUITRY**

(75) Inventors: **Barry A. Hoberman**, Cupertino, CA (US); **Daniel L. Hillman**, San Jose, CA (US); **William G. Walker**, Saratoga, CA (US); **John M. Callahan**, San Ramon, CA (US); **Michael A. Zampaglione**, San Jose, CA (US); **Andrew Cole**, Sunnyvale, CA (US)

(73) Assignee: **Conversant Intellectual Property Management Inc.**, Ottawa, Ontario (CA)

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USPC **326/27; 326/38; 326/81**

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CPC H03K 19/00361; H03K 19/0016; H03K 17/16
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See application file for complete search history.

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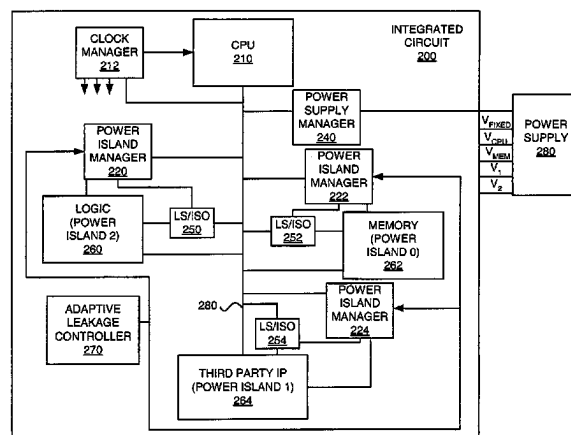
Primary Examiner — Don Le

(74) *Attorney, Agent, or Firm* — Conley Rose, P.C.; J. Robert Brown, Jr.

(57) **ABSTRACT**

An integrated circuit includes first circuitry and sleep transistor circuitry. The first circuitry receives input signals and processes the input signals. The first circuitry also retains data in a sleep state that has low leakage. The sleep transistor circuitry is coupled to the first circuitry and receives a sleep signal that has a negative voltage. The sleep circuitry reduces power consumption of the first circuitry in the sleep state to have low leakage based on the sleep signal while retaining the data in the first circuitry.

18 Claims, 12 Drawing Sheets



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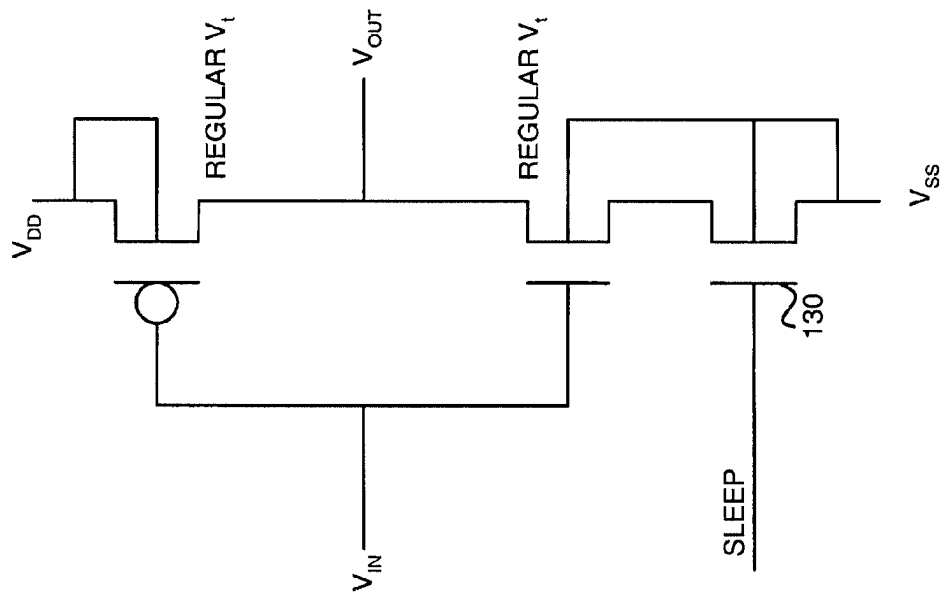


FIG. 1
PRIOR ART

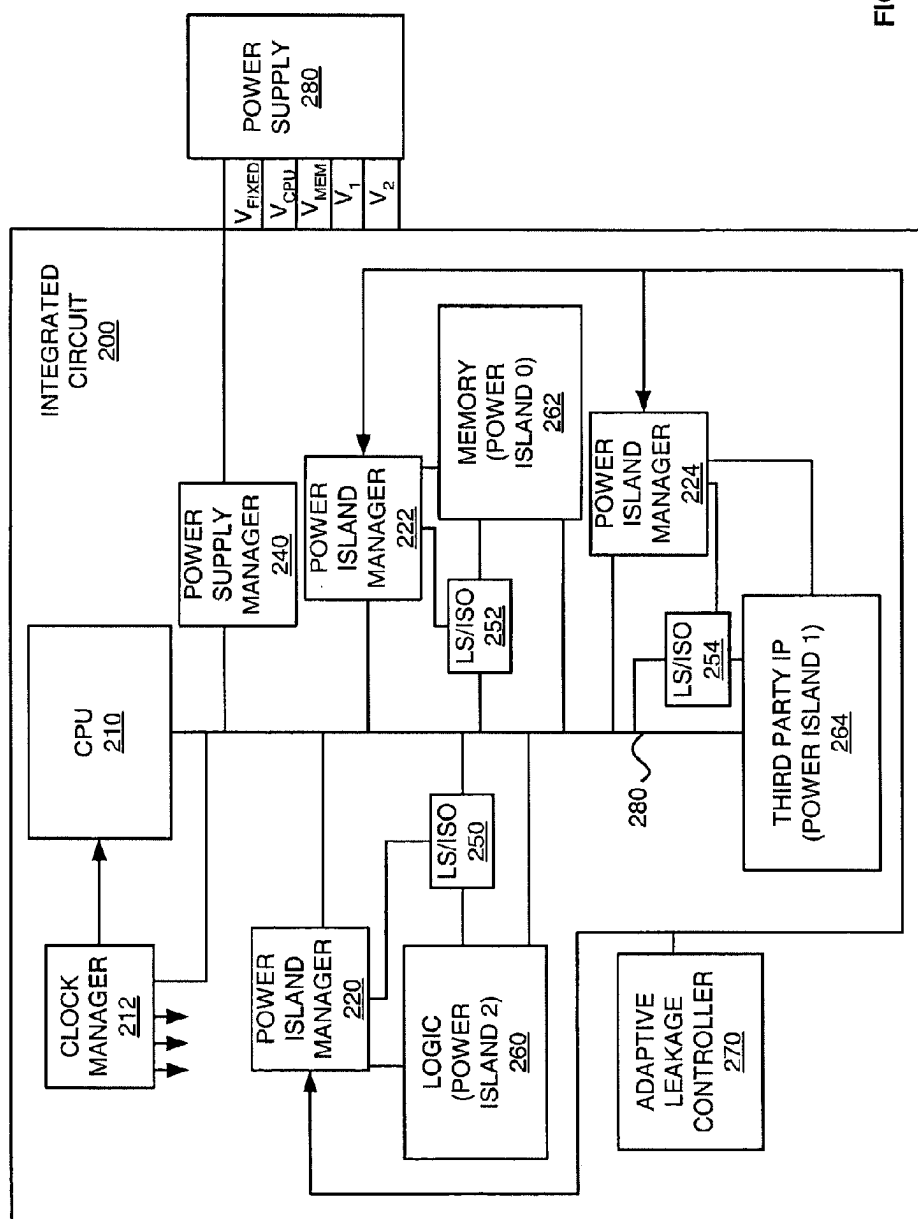


FIG. 2

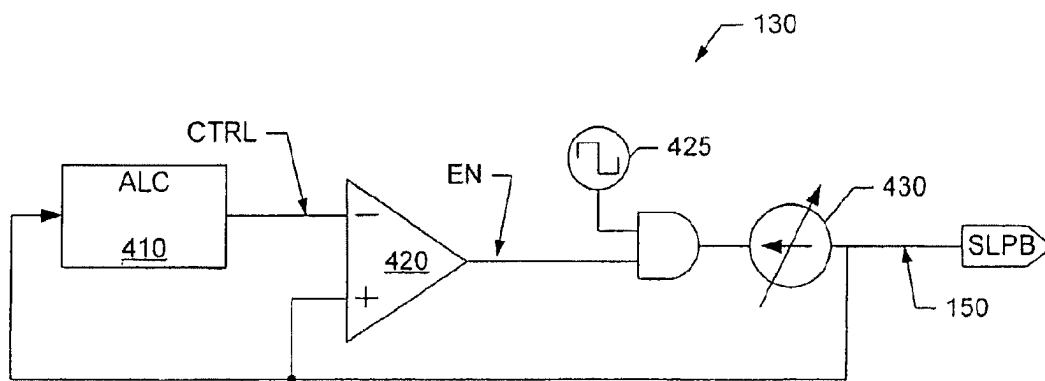


FIG. 2A

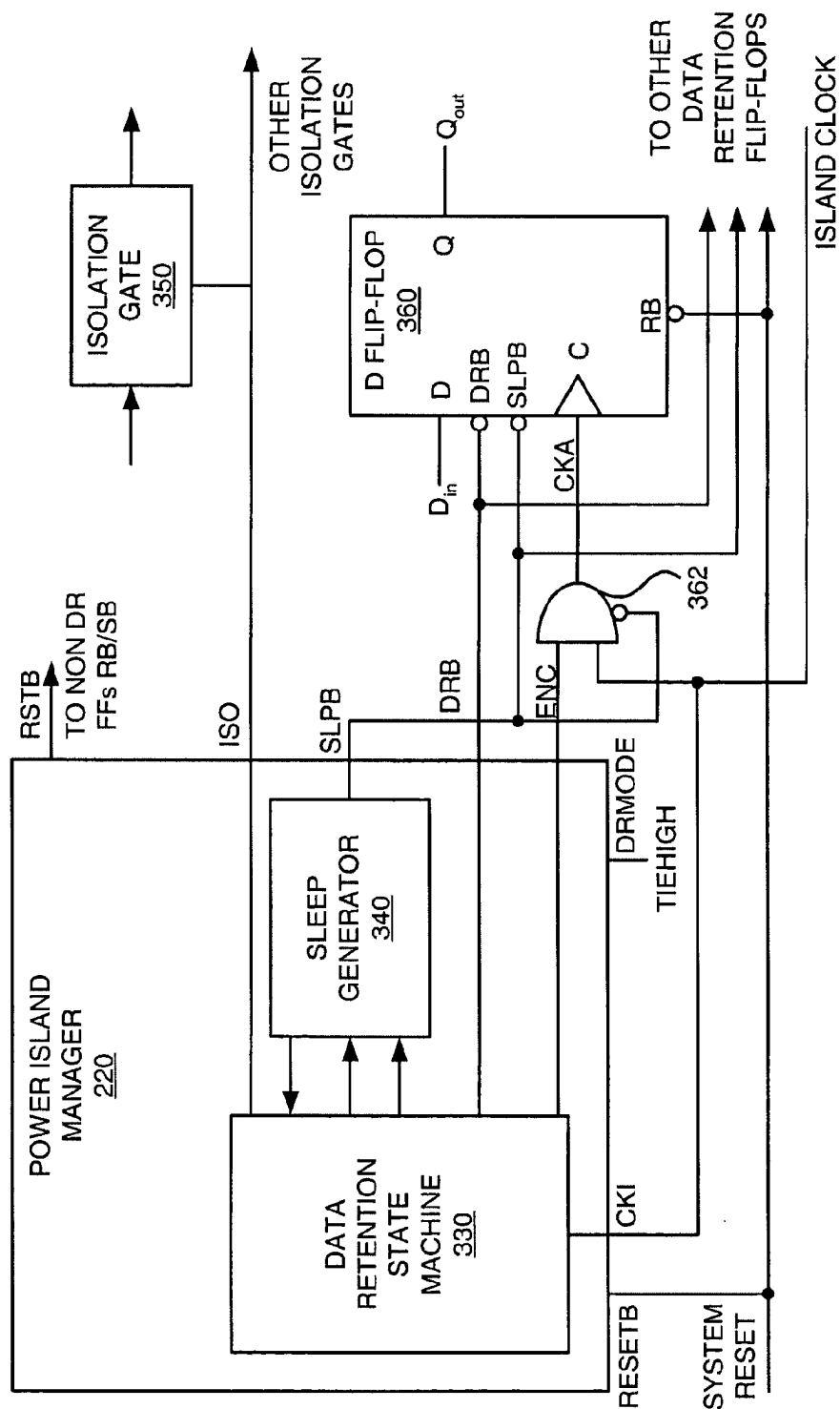


FIG. 3

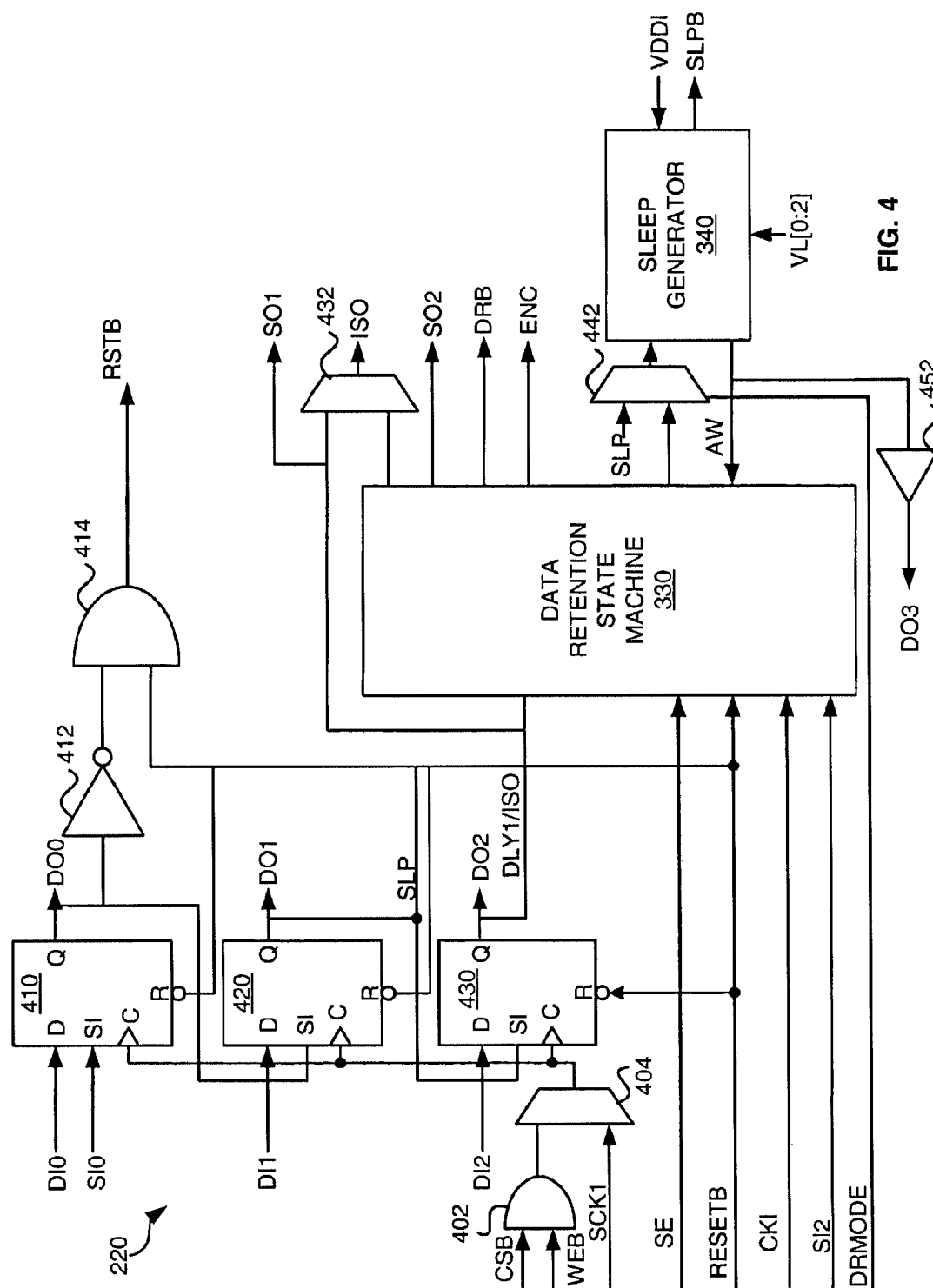
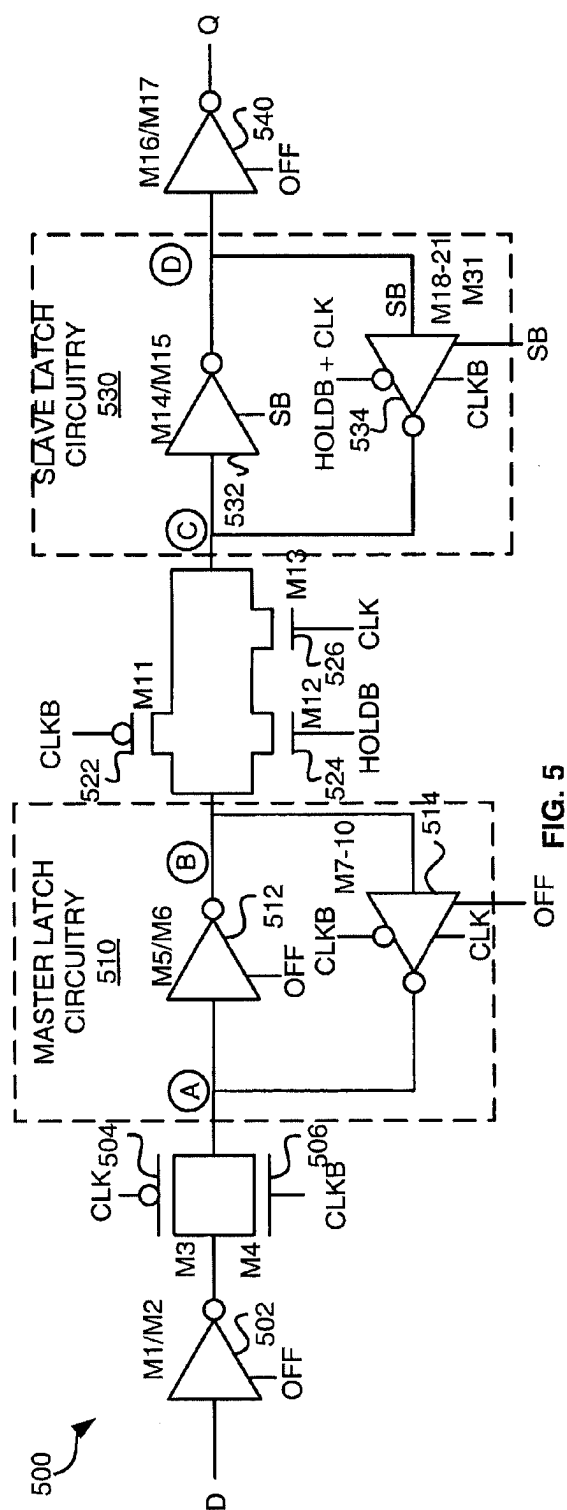


FIG. 4



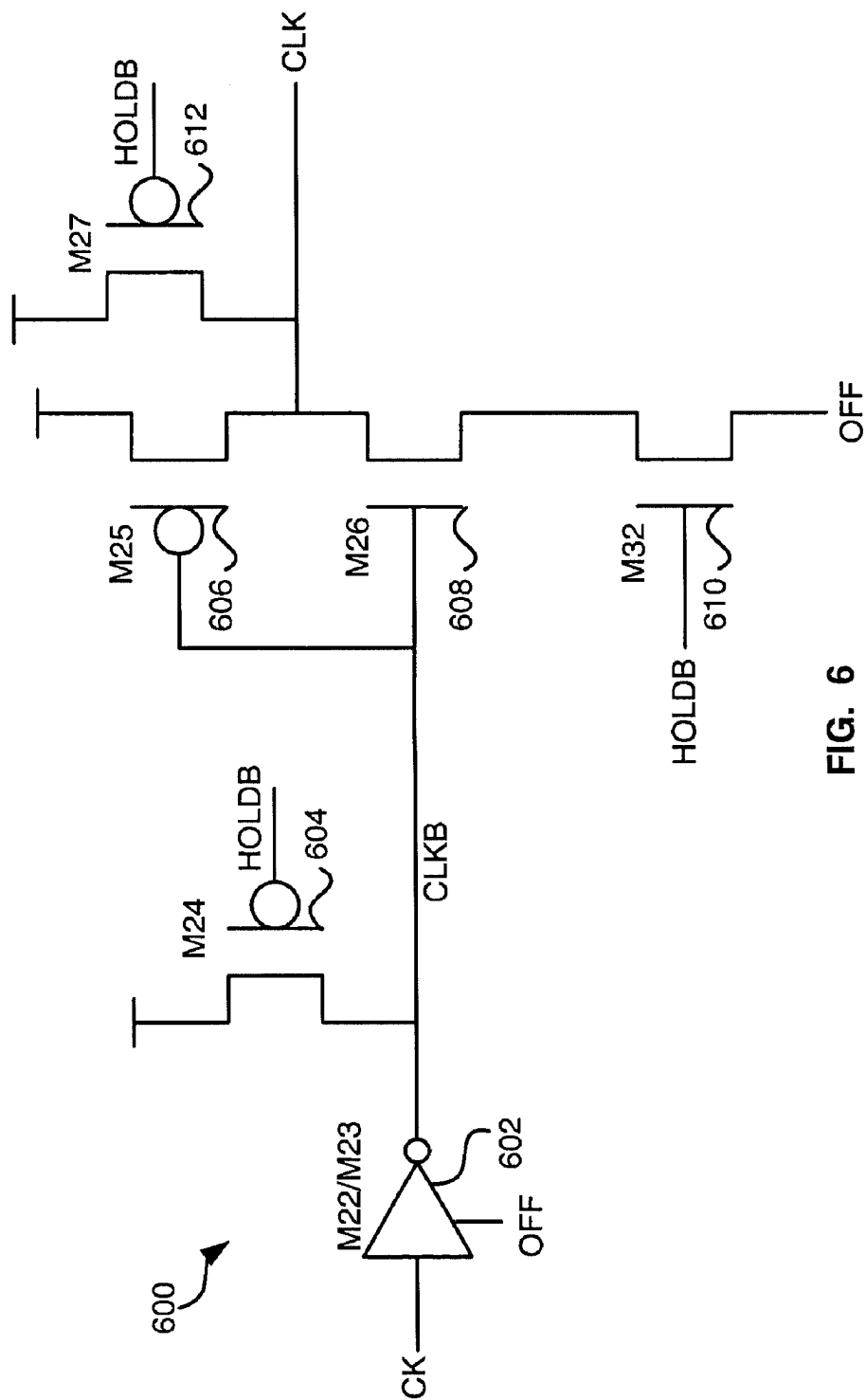


FIG. 6

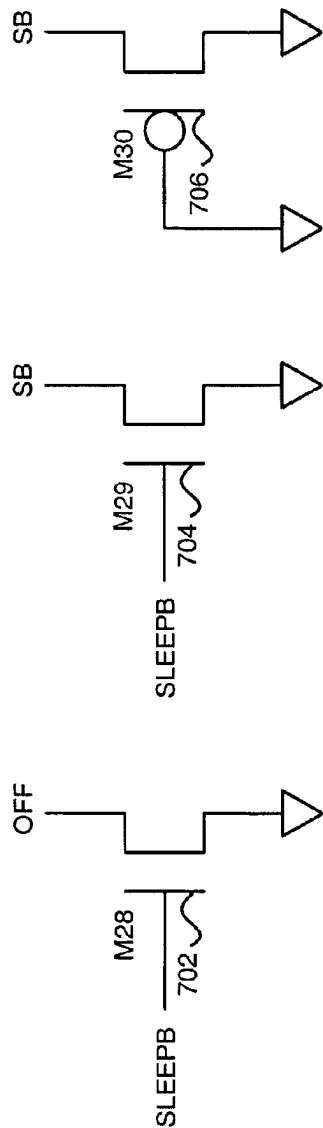


FIG. 7C

FIG. 7B

FIG. 7A

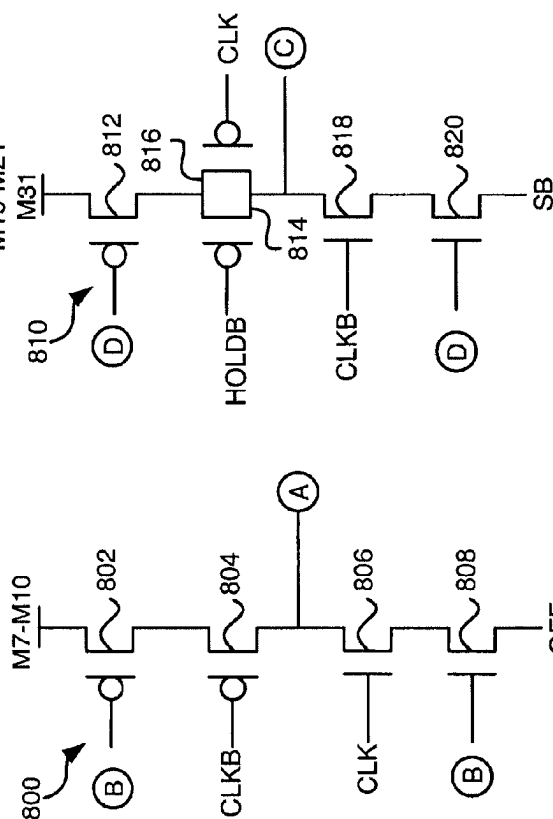


FIG. 8B

FIG. 8A

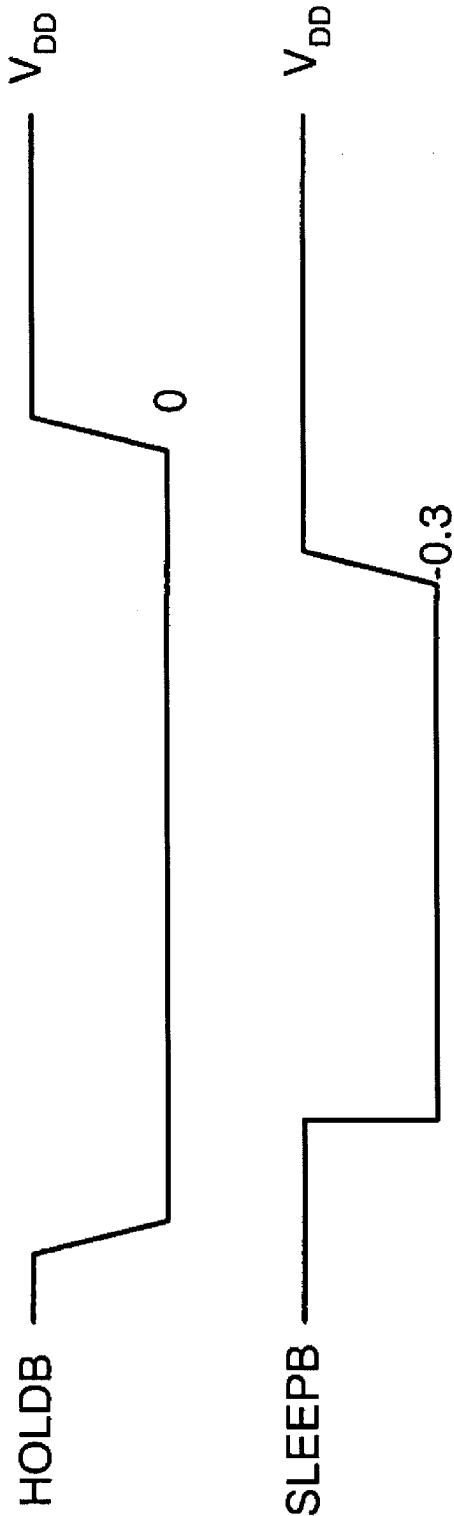


FIG. 9

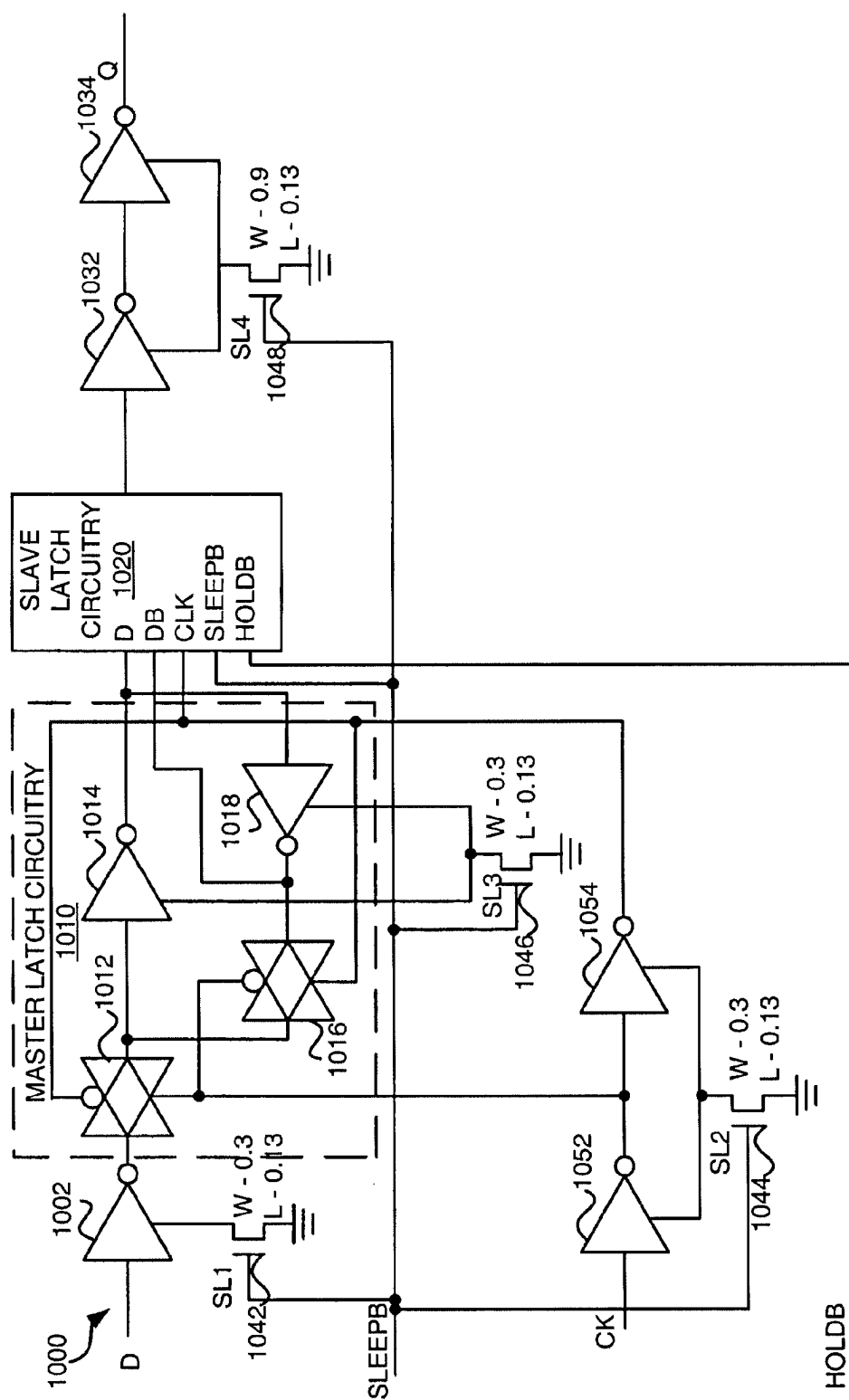
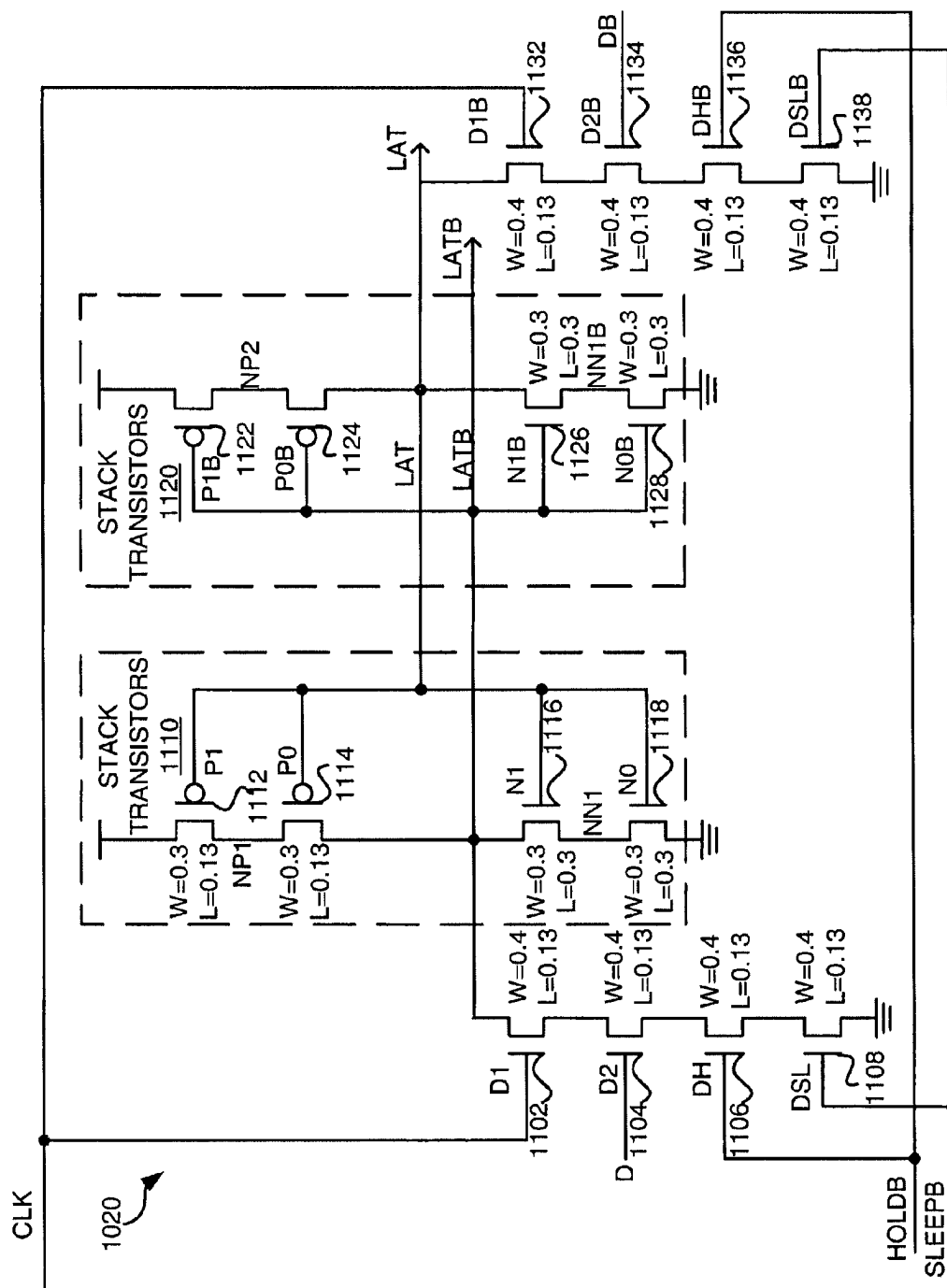
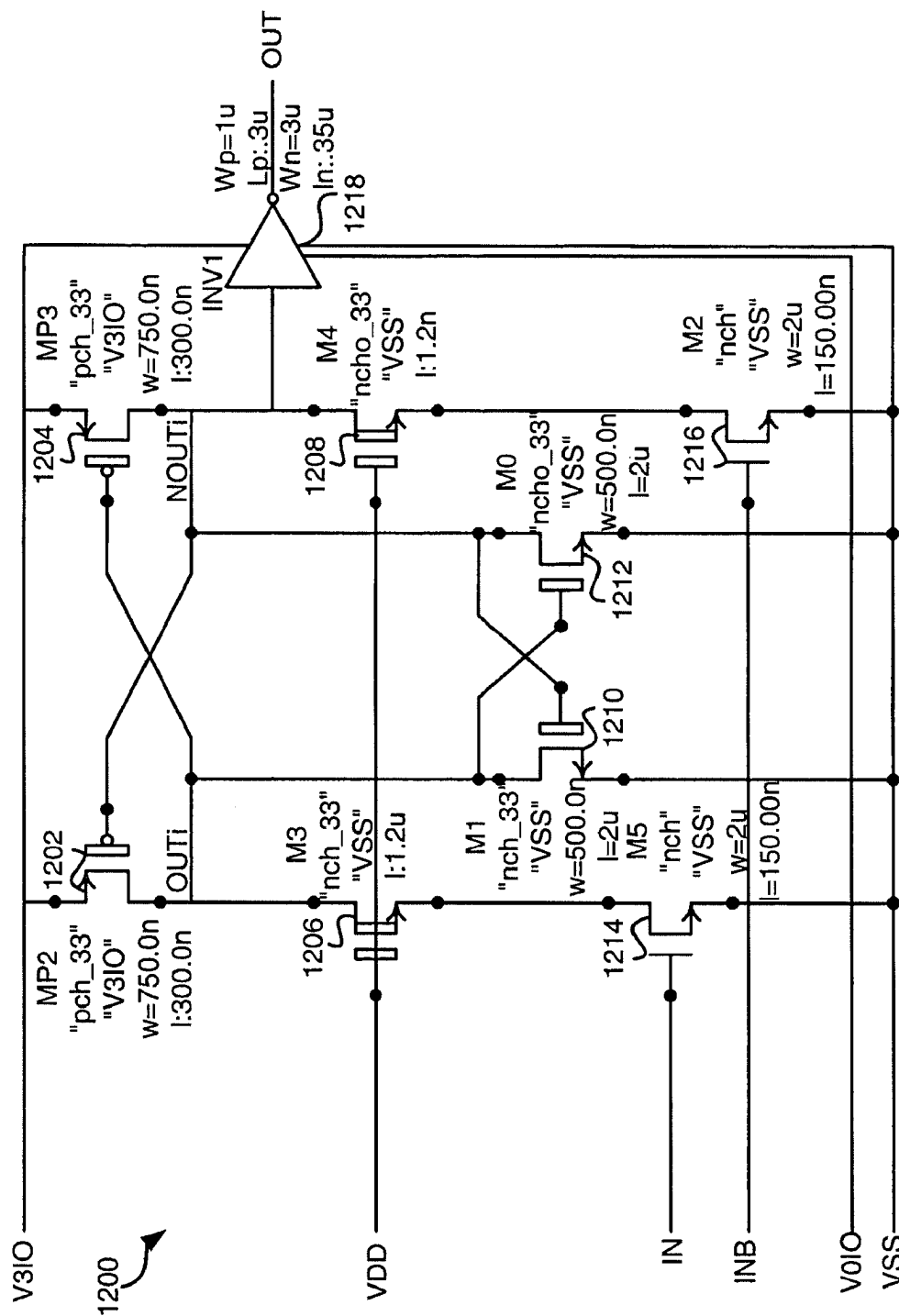


FIG. 10





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LOW LEAKAGE AND DATA RETENTION CIRCUITRY

RELATED APPLICATIONS

This application is a continuation of U.S. application Ser. No. 13/074,291, filed Mar. 29, 2011 now U.S. Pat. No. 8,253,438, which is a continuation of U.S. application Ser. No. 12/542,352, filed Aug. 17, 2009 (now U.S. Pat. No. 7,940,081), which is a continuation of U.S. application Ser. No. 12/284,311, filed Sep. 19, 2008 (now U.S. Pat. No. 7,592,837), which is a continuation of U.S. application Ser. No. 11/998,725, filed Nov. 30, 2007 (now U.S. Pat. No. 7,443,197), which is a continuation of U.S. application Ser. No. 11/732,181, filed Apr. 2, 2007 (now U.S. Pat. No. 7,348,804), which is a divisional and claims the priority benefit of U.S. application Ser. No. 11/041,687 filed Jan. 20, 2005 (now U.S. Pat. No. 7,227,383), which claims the priority benefit of U.S. Provisional Application No. 60/546,574, filed Feb. 19, 2004 and U.S. Provisional Application No. 60/586,565, filed Jul. 9, 2004.

The entire teachings of the above applications are incorporated herein by reference.

BACKGROUND OF THE INVENTION

1. Field of the Invention

The present invention relates generally to integrated circuits, and more particularly to low leakage and data retention circuitry.

2. Description of the Related Art

Most integrated circuits have a design goal to reduce the overall power consumption. The total power consumed by an integrated circuit includes dynamic power consumption and standby leakage current consumption. The challenge in designing an integrated circuit is to reduce the dynamic power and leakage power, while maintaining performance and cost goals for the integrated circuit.

In complementary metal oxide semiconductors (CMOS), various types of leakage occur such as pn junction reverse-bias current, subthreshold leakage, oxide tunneling current, gate current due to hot-carrier injection, gate-induced drain leakage, and channel punch through current. When the threshold voltage for a CMOS transistor is reduced for higher performance, the leakage power is significant in the total power consumption of the CMOS circuit.

There are two approaches in reducing the leakage power for CMOS circuits. The first approach is a process level technique that controls the doping profile of the transistor. The other approach is a circuit level technique where voltages at the different device terminals such as the drain, source, gate, and body are controlled. Some circuit level techniques are discussed below.

One circuit level technique is stacking transistors, which is also called self-reverse bias. When more than one transistor in a stack of series-connected transistors is turned off, the subthreshold leakage current is reduced. One problem with the transistor stack is that only a three times reduction in leakage current is achieved. Another circuit level technique is a multiple threshold voltage design. Both high- and low-threshold transistors are on the same chip to deal with the leakage problem. The high-threshold transistors suppress the subthreshold leakage current. The low-threshold transistors are used to achieve higher performance. One problem with a multiple threshold design is that process complexity and costs are increased.

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Another circuit level technique is a multiple body bias in which the body voltage is changed to modify the threshold voltage. If separate body biases are applied to different NMOS transistors, the transistor cannot share the same well, which requires triple well technologies. One problem is that well biasing consumes a lot of chip area and requires extra power supplies for each cell. This technique also increases process complexity and the leakage reduction is not optimal.

Another technique for reducing leakage is a sleep transistor. FIG. 1 depicts prior art circuitry including a sleep transistor. For NMOS sleep transistors, one or more NMOS transistors are added to logic gates in series with the cell transistors to VSS. The NMOS sleep transistors act as a switch to turn on and off the logic gate. In FIG. 1, the sleep transistor **130** is turned on (gate to VDD) during normal cell operation. When the cell is idle, the sleep transistor **130** is turned off (gate tied to VSS) to reduce the leakage current of the cell. Sleep transistors can also be PMOS transistors. One problem with sleep transistors is that if all logic has sleep transistors, the logic will lose their state information.

SUMMARY OF THE INVENTION

In an exemplary embodiment of the presently disclosed invention, a data retention circuit is provided. The exemplary circuit includes an input/output pad cell that itself includes level shifter circuitry, the level shifter circuitry having inputs and outputs. Output latching circuitry is also provided as a part of the data retention circuit. The output latching circuitry includes two transistors. The transistors are coupled to the outputs of the level shifter circuitry and retain a state of the level shifter circuitry based on the state of the inputs. A leakage optimization circuit is also included, the leakage optimization circuit is configured to simultaneously decrease leakage power in conjunction with the state retention of the output latching circuitry.

In another embodiment of the presently disclosed invention, a system for controlling power consumption within an integrated circuit is disclosed. The system includes a power island, the power island includes a first circuit. The first circuit of the power island is configured to receive an input signals and a hold signal. The circuit is further configured to process the input signals and retain data in a sleep state having low leakage. The first circuit is further configured to retain the data based on the hold signal. The system further includes a sleep transistor, which is coupled to the first circuit. The sleep transistor is configured to receive a negative voltage sleep signal and reduce power consumption of the first circuit in the sleep state. As a result, the first circuit has low leakage based on the sleep signal while simultaneously retaining the data.

BRIEF DESCRIPTION OF THE DRAWINGS

The foregoing will be apparent from the following more particular description of example embodiments of the invention, as illustrated in the accompanying drawings in which like reference characters refer to the same parts throughout the different views. The drawings are not necessarily to scale, emphasis instead being placed upon illustrating embodiments of the present invention.

FIG. 1 is an illustration of circuitry including a sleep transistor in the prior art;

FIG. 2 is an illustration of an integrated circuit with a power supply in an exemplary implementation of the invention;

FIG. 2A is a block diagram of a leakage manager system for minimizing state leakage of a logic gate by application of a negative voltage to a sleep transistor.

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FIG. 3 is an illustration of a power island manager with an isolation gate and a D flip-flop in an exemplary implementation of the invention;

FIG. 4 is an illustration of a power island manager in an exemplary implementation of the invention;

FIG. 5 is an illustration of a D/Q portion of flip-flop circuitry in an exemplary implementation of the invention;

FIG. 6 is an illustration of a CK portion of flip-flop circuitry in an exemplary implementation of the invention;

FIG. 7A is an illustration of a sleep transistor for an OFF node in an exemplary implementation of the invention;

FIG. 7B is an illustration of a sleep transistor for an SB node in an exemplary implementation of the invention;

FIG. 7C is an illustration of a moderate impedance transistor for an SB node in an exemplary implementation of the invention;

FIG. 8A is an illustration of circuitry for a tristate inverter in the master latch in an exemplary implementation of the invention;

FIG. 8B is an illustration of circuitry for a tristate inverter in the slave latch in an exemplary implementation of the invention;

FIG. 9 is an illustration of a HOLDB and SLEEPB signals in an exemplary implementation of the invention;

FIG. 10 is an illustration of circuitry for low leakage and data retention in an exemplary implementation of the invention;

FIG. 11 is an illustration of slave latch circuitry in an exemplary implementation of the invention; and

FIG. 12 is an illustration of circuitry for a level shifter for an I/O pad in an exemplary implementation of the invention.

DETAILED DESCRIPTION OF THE INVENTION

A description of example embodiments of the invention follows.

As shown in the exemplary drawings wherein like reference numerals indicate like or corresponding elements among the figures, exemplary embodiments of a system and method according to the present invention are described below in detail. It is to be understood, however, that the present invention may be embodied in various forms. Therefore, specific details disclosed herein are not to be interpreted as limiting, but rather as a basis for the claims and as a representative basis for teaching one skilled in the art to employ the present invention in virtually any appropriately detailed system, structure, method, process or manner.

Power Island Manager—FIGS. 2-4

In some embodiments, an integrated circuit can be delineated into power islands. Power consumption can then be controlled within the power island. A power island manager provides control signals to the power island to control power consumption of the power island. In some embodiments, the low leakage, data retention circuitry is located within the power islands.

FIG. 2 depicts an illustration of an integrated circuit 200 with a power supply 280 in an exemplary implementation of the invention. The integrated circuit 200 includes a central processing unit (CPU) 210, a clock manager 212, power island managers 220, 222, and 224, a power supply manager 240, level shifter/isolation gates (LS/ISO) 250, 252, and 254, logic (power island 2) 260, memory (power island 0) 262, third party intellectual property (IP) (power island 1) 264, adaptive leakage controller (ALC) 270, and bus 280.

A power island is any section, delineation, partition, or division of an integrated circuit where power consumption is controlled within the section, delineation, partition, or divi-

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sion. In some embodiments, the power islands are delineated based on geographic factors of the integrated circuit. In some embodiments, the power islands are delineated based on functional IP units of the integrated circuit 200. In this example depicted in FIG. 2, power islands are delineated by memory 262, logic 260, and third party IP 264. Power islands are discussed in further detail in pending U.S. application Ser. No. 10/840,893 entitled “Managing Power on Integrated Circuits Using Power Islands” filed on May 7, 2004, which is hereby incorporated by reference.

The power island managers 220, 222, and 224 are any circuitry, device, or system configured to provide control signals to a power island to control power within the power island. The power island managers 220, 222, and 224 can dynamically change the power consumption of the power islands based on the needs and operation of the integrated circuit 200. The power island managers 220, 222, 224 may select a clock, change clock frequency, or modify the voltage within the power island to control the power consumption of the power island.

The ALC 270 provides control signals to compensate for process and temperature variation to provide the optimum voltage to be applied to sleep transistors in the power islands. The ALC 270 is described in further detail U.S. patent application Ser. No. 10/996,739 entitled “Systems and Methods for Minimizing Static Leakage of an Integrated Circuit” filed on Nov. 17, 2004.

FIG. 2A is a block diagram of a leakage manager system 290 for minimizing static leakage of a logic gate by application of a negative voltage to a sleep transistor in accordance with an example embodiment. The leakage manager system 290 comprises an adaptive leakage controller (ALC) 291, a negative voltage regulator 292, and a charge pump 294. The charge pump 294 generates a negative voltage 295 (SLPB). The ALC 291 determines whether to adjust the negative voltage 295. The ALC 291 generates a signal (depicted as CTRL) depending on the determination. The negative voltage regulator 292 adjusts the negative voltage 295 depending on the CTRL signal.

As described further herein, the negative voltage regulator 292 of one embodiment generates an enable (EN) signal to the charge pump 294 to enable the charge pump 294 to increase the magnitude of the negative voltage 295 (i.e., to make the negative voltage 295 more negative). If the EN signal is low, an alternating signal from an oscillator 293 to the charge pump 294 is disabled, preventing the charge pump 294 from increasing the magnitude of the negative voltage 295. Alternatively, if the EN signal is high, the alternating signal from the oscillator 293 is enabled so that the charge pump 294 will increase the magnitude of the negative voltage 295. Because the negative voltage regulator 292 toggles the EN signal on or off depending on whether the ALC 291 determines to adjust the negative voltage 295, the leakage manager system 290 maintains the negative voltage 295 at a particular negative voltage to minimize static leakage of the logic gate.

Under normal operation where the digital logic block is to operate, the sleep control receives a signal (sleep input, polarity unimportant here) to disable the charge pump and raise V_{sleep} voltage to V_{DD} .

Under idle operation, where the digital logic block is to sleep (change to a low leakage current state), the Charge Pump Control Logic (CPCL) sends a clock signal and an enable signal to the Negative Voltage Charge Pump (NVCP) to first rapidly drop the V_{sleep} signal to V_{SS} . Then the charge pump begins to push the V_{sleep} voltage below V_{SS} and continues to do so until it receives a pause signal from the CPCL. The Negative Bias Voltage Bias Regulator (NVBR) monitors

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the V_{sleep} voltage until a desirable reduction of the transistor current I_{off} has been achieved. At that point it sends a signal to the CPCL to initiate a Pause signal to the NVCP. As time passes the V_{sleep} voltage will slowly drift upwards toward V_{SS} and at a preset transistor I_{off} the NVBR sends a signal to the CPCL to restart the NVCP to restore the V_{sleep} negative voltage to achieve the desired I_{off} .

FIG. 3 depicts an illustration of the power island manager 220 with an isolation gate 350 and a D flip-flop 360 in an exemplary embodiment of the invention. The power island manager 220 includes a data retention state machine 330 and a sleep generator 340 that are coupled to each other.

The power island manager 220 is coupled to the isolation gate 350 by the ISO signal. The ISO signal is also coupled to other isolation gates. The data retention state machine 330 is coupled to DRB input of the D flip-flop 360 via the DRB signal. The data retention state machine 330 is also coupled to the AND gate 362 via the ENC signal. The clock island (CKI) signal is coupled to the data retention state machine 330 and the AND gate 362. The sleep generator 340 is coupled to the D flip-flop 360 and the AND gate 362 via the SLPB signal. The output of the AND gate 362 is coupled to the C input of the D flip-flop 360 via the CKA signal. The system reset signal is coupled to the RESETB input of the power island manager 220 and the RB input of the D flip-flop 360. The SLPB signal, the DRB signal, and the system reset signal are coupled to other data retention flip-flops.

FIG. 4 depicts an illustration of a power island manager 220 in an exemplary embodiment of the invention. The power island manager 220 includes an AND gate 402, a multiplexer (MUX) 404, a D flip-flop 410, an inverter 412, an AND gate 414, a D flip-flop 420, a D flip-flop 430, the data retention state machine 330, a MUX 432, a sleep generator 340, and a buffer 452.

The DI0 pin is coupled to the D input of the D flip-flop 410. The SI0 pin is coupled to the S1 input of the D flip-flop 410. The CSB and the WEB pins are coupled to the inputs of the AND gate 402. The output of the AND gate 402 and the SCK1 pin are coupled to the input of the MUX 404. The output of the MUX 404 is coupled to the C inputs of the D flip-flop 410, the D flip-flop 420, and the D flip-flop 430. The Q output of the D flip-flop 410 is coupled to the DO0 pin, which is coupled to the input of the inverter 412 and the SI input of the D flip-flop 420. The DI1 pin is coupled to the D input of the D flip-flop 420. The Q output of the D flip-flop 420 is coupled to the DO1 pin, which is coupled to the input of the AND gate 414 and the SI input of the D flip-flop 430. The output of the AND gate 414 is coupled to the RSTB pin. The DI2 pin is coupled to the D input of the D flip-flop 430. The Q output of the D flip-flop 430 is coupled to the DO2 pin, which is coupled to the DLY1/ISO pin. The DLY1/ISO pin is coupled to the SO1, the input of the MUX 432, and the data retention state machine 330.

The RESETB pin is coupled to the R input of the D flip-flop 430, the D flip-flop 420, and the D flip-flop 410. The SE pin, the RESETB pin, the CKI pin, and the SI2 pin are coupled to the data retention state machine 330. The data retention state machine 330 is coupled to the input of the MUX 432, the SO2 pin, the DRB pin, the ENC pin, and the input of the MUX 442. The output of the MUX 442, the VDDI pin, and the VL[0:2] are coupled to the sleep generator 340. The sleep generator 340 is coupled to the SLPB pin. The sleep generator 340 is coupled to the data retention state machine 330 via the AW pin and the input of the buffer 452. The output of the buffer 452 is coupled to the DO3 pin. The DRMODE pin is coupled to the MUX 442.

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In operation, the power island manager 220 has a three bit register for controlling a power island for some embodiments. D [0], with input DI0 and output DO0, is an island reset for re-initializing a power island. This bit is combined with RESETB to form RSTB to re-initialize the power island whenever RESETB or the D [0] is active. D [1], with input DI1 and output DO1, is a sleep bit. When the D [1] bit is set to one, the power island goes into a low leakage state. D [2], with input DI2 and output DO2, is a DLY1/Isolate bit. When DRMODE is tied to low, the D [2] bit, when set to one, will add one clock cycle delay between DRB going active and SLPB going active. When DRMODE is tied high, the D [2] bit, when set to one, will activate isolation of the power island. D [3], such as DO3, is an awake bit. This D [3] bit goes high when SLPB is high. This can be used by software to determine when a power island is out of the sleep state.

The power island manager 220 has two operating modes: one that supports power islands with data retention flip-flops and one that does not. When the DRMODE pin is tied high, a power island is put to sleep by writing a one to D[1]. The data retention state machine 330 performs the timing. The isolate (ISO) signal goes active when the sleep bit is written to a one, and the enable clock (ENC) and the data retention (DRB) will go low after synchronization to the power island clock (CKI). One or two clock cycles later the sleep (SLPB) goes low. To come out of sleep mode, a zero is written to D[1]. In some embodiments, all clock buffers in the power islands can be put to sleep to further minimize leakage. Software can determine when the power island has come out of sleep by reading when DO3 is high.

The System Reset is typically applied once after initial system power up. In some embodiments, the System Reset goes to all data retention flip-flops. The System Reset signal and DI0 bar are combined in a logical AND (RSTB output) to provide initialization to non data retention flip-flops. To create a power island reset, D[0] is set to a one and then cleared to a zero by software.

When the DRMODE is tied low, the power island manager 220 can also provide the control signals for a power island without data retention flip-flops. The power island manager 220 may have a hardware driven method and a software driven method for interfacing to power islands without data retention flip-flops. The software sequence has the following sequence:

Write 04/turn on isolation
Write 06/turn on sleep, isolation on/come out of sleep
Write 05/turn sleep off, reset island, isolation on/wait for sleep to go high
Read/test for DO3=1; sleep is high
Write 00/turn isolation off, normal operation

The hardware driven method uses a clock to sequence the state machine. The only action software takes is to write the sleep bit (DI1) to a one to go into sleep and write a zero to the sleep bit to go out of sleep. Software can determine when the island has come out of sleep by reading when DO3 is high.

In some embodiments, the power island manager 220 contains two scan chains because some of the flip-flops are clocked on the positive and some on the negative. The scan chain enable pin switches the clock on scan chain 1 (SI1 is the input; SO1 is the output), the registers, to CKS1. Scan chain 2 (SI2 is the input; SO2 is the output) is connected to the data retention state machine 330 flip-flops that are clocked on the negative edge of CKI. A separate scan out is provided for each clock domain.

In some embodiments, the SLPB net uses p-type antenna diodes. Since the SLPB net may go to a negative voltage, an n-type antenna diode can cause excessive leakage to ground.

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The leakage can cause SLPB not to go negative and may not work properly. The CSB pin is a chip select pin. The WEB pin is the write enable pin. The VL [2:0] is the leakage control voltage value set by the ALC 270 (FIG. 2). The VDDI is the VDD from the power island.

Low Leakage, Data Retention Circuitry—FIGS. 5, 6, 7A-C, 8A-8B, and 9-12

FIGS. 5, 6, 7A-C, and 8A-8B disclose one embodiment for low leakage, data retention circuitry. In this embodiment, in sleep mode, the circuit parts of a flip-flop that do not require data retention are coupled to ground through a sleep transistor. The gate of the sleep transistor is coupled to a sleep signal that can be driven to a negative voltage such as $-0.3V$. Thus, the leakage in these circuit parts of the flip-flop is eliminated (reduced). When not in a sleep state, the sleep transistor has a gate value equal to or greater than the VDD supply, which effectively grounds the circuit.

The circuit parts that require data retention are coupled to ground through two transistors. One transistor acts effectively to ground the circuit above when not in sleep mode just as the sleep transistor described above. The other transistor is a PMOS device with the gate tied to ground, which provides medium impedance to ground. The voltage drop across this transistor acts to reduce the leakage by increasing the source bias of the NMOS transistors and simultaneously reduces the voltage across the circuit. In this embodiment, the data is retained in a sleep state and reduces the leakage by a factor of 22.

FIG. 5 depicts an illustration of a D/Q portion 500 of the flip-flop circuitry in an exemplary implementation of the invention. The D/Q portion 500 of the flip-flop circuitry includes an inverter 502, a M3 PMOS transistor 504, an M4 NMOS transistor 506, master latch circuitry 510, an M11 PMOS transistor 522, an M12 NMOS transistor 524, an M13 NMOS transistor 526, slave latch circuitry 530, and an inverter 540.

The D signal input is the input of the inverter 502, which includes transistors M1 and M2. The source of the inverter 502 is coupled to the node OFF, which is described below in FIG. 7A. The output of the inverter 502 is coupled to the M3 PMOS transistor 504 and the M4 NMOS transistor 506. The gate of the M3 PMOS transistor 504 is coupled to the CLK signal input. The gate of the M4 NMOS transistor 506 is coupled to the CLKB signal input.

The master latch circuitry 510 includes the inverter 512 and the inverter 514. The inverter 514 forms a feedback loop with the inverter 512, where the output of the inverter 512 is coupled to the input of the inverter 514 and the output of the inverter 514 is coupled to the input of the inverter 512. The inverter 512 corresponds to transistor M5 and M6. The inverter 514 corresponds to transistors M7-M10. The input of the inverter 512 is coupled to node A, which is described in FIG. 8A below. The source of the inverter 512 is also coupled to node OFF, which is described below in FIG. 7A. The output of the inverter 512 is coupled to node B, which is described below in FIG. 8A. The source of the inverter 514 is coupled to node OFF, which is described below in FIG. 7A. The PMOS gate of the inverter 514 is coupled to the CLKB signal input. The NMOS gate of the inverter 514 is coupled to the CLK signal input.

The M11 PMOS transistor 522 is in parallel to the M12 NMOS transistor 524 and the M13 NMOS transistor 526, which are in series. The gate of the M11 PMOS transistor 522 is coupled to the CLKB signal input. The gate of the M12 NMOS transistor 524 is coupled to the HOLDB signal input. The gate of the M13 NMOS transistor 526 is coupled to the CLK signal input.

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The slave latch circuitry 530 includes the inverter 532 and the inverter 534. The inverter 534 forms a feedback loop with the inverter 532, where the output of the inverter 532 is coupled to the input of the inverter 534 and the output of the inverter 534 is coupled to the input of the inverter 532. The inverter 532 corresponds to transistor M14 and M15. The inverter 534 corresponds to transistors M18-21 and M31. The input of the inverter 532 is coupled to node C, which is described in FIG. 8B below. The source of the inverter 532 is also coupled to node SB, which is described below in FIGS. 7B-C. The output of the inverter 532 is coupled to node D, which is described below in FIG. 8B. The source of the inverter 534 is coupled to node SB, which is described below in FIGS. 7B-C. The PMOS gates of the inverter 534 are coupled to the HOLDB and CLK signal inputs. The NMOS gate of the inverter 534 is coupled to the CLKB signal input.

The output of the inverter 532 is coupled to the input of the inverter 540. The inverter 540 corresponds to transistors M16 and M17. The source of the inverter 540 is also coupled to node OFF, which is described below in FIG. 7A. The output of the inverter 540 is the Q signal output.

FIG. 6 depicts a CK portion 600 of the flip-flop circuitry in an exemplary implementation of the invention. The CK portion 600 of the flip-flop circuitry includes an inverter 602, an M24 PMOS transistor 604, an M25 PMOS transistor 606, an M26 NMOS transistor 608, an M32 NMOS transistor 610, and an M27 PMOS transistor 612.

The CK signal input is the input of the inverter 602, which includes transistors M22 and M23. The source of the inverter 602 is coupled to node OFF, which is described below in FIG. 7A. The output of the inverter 602 is coupled to the drain of the M24 PMOS transistor 604 and the node CLKB. The gate of the M24 PMOS transistor 604 is coupled to the HOLDB signal input. The output of the inverter 602 is also coupled to the M25 PMOS transistor 606 and the M26 NMOS transistor 608. The M25 PMOS transistor 606, the M26 NMOS transistor 608, and the M32 NMOS transistor 610 are coupled in series. The gate of the M32 NMOS transistor 610 is coupled to the HOLDB signal input.

The CLK signal output is coupled to the drain of the M25 PMOS transistor 606, the drain of the M26 NMOS transistor 608, and the drain of the M27 PMOS transistor 612. The gate of the M27 PMOS transistor 612 is coupled to the HOLDB signal input.

FIG. 7A depicts a sleep transistor 702 for the OFF node in an exemplary implementation of the invention. The sleep transistor 702 is an NMOS transistor that corresponds to transistor M28. The drain of the sleep transistor 702 is coupled to the OFF node. The gate of the sleep transistor 702 is coupled to the SLEEPB signal input. The source of the sleep transistor 702 is coupled to ground. In some embodiments, the OFF node can be separated into two or more nodes each having its own NMOS sleep transistor.

FIG. 7B depicts a sleep transistor 704 for the SB node in an exemplary implementation of the invention. The sleep transistor 704 is an NMOS transistor that corresponds to transistor M29. The drain of the sleep transistor 704 is coupled to the SB node. The gate of the sleep transistor 704 is coupled to the SLEEPB signal input. The source of the sleep transistor 704 is coupled to ground.

FIG. 7C depicts a sleep transistor 706 for the SB node in an exemplary implementation of the invention. The sleep transistor 706 is a PMOS transistor that corresponds to transistor M30. The source of the sleep transistor 706 is coupled to the SB node. The gate and drain of the sleep transistor 706 are coupled to ground.

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FIG. 8A depicts circuitry **800** for the tristate inverter in the master latch in an exemplary implementation of the invention. The circuitry **800** for the master latch includes a PMOS transistor **802**, a PMOS transistor **804**, an NMOS transistor **806**, and an NMOS transistor **808** that are coupled together in series. The gates of the PMOS transistor **802** and the NMOS transistor **808** are coupled to the node B. The gate of the PMOS transistor **804** is coupled to the CLKB signal input. The gate of the NMOS transistor **806** is coupled to the CLK signal input. The drains of the PMOS transistor **804** and the NMOS transistor **806** are coupled to node A. The source of the NMOS transistor **808** is coupled to node OFF.

FIG. 8B depicts circuitry **810** for the tristate inverter in the slave latch in an exemplary implementation of the invention. The circuitry **810** for the slave latch includes a PMOS transistor **812**, a PMOS transistor **814**, a PMOS transistor **816**, an NMOS transistor **818**, and an NMOS transistor **820**. The PMOS transistor **812** is coupled to the PMOS transistor **814** and the PMOS transistor **816** that are parallel to each other. The PMOS transistor **814** and the PMOS transistor **816** are coupled to the NMOS transistor **818**, which is also coupled to the NMOS transistor **820**.

The gates of the PMOS transistor **812** and the NMOS transistor **820** are coupled to the node D. The gate of the PMOS transistor **814** is coupled to the HOLDB signal input. The gate of the PMOS transistor **816** is coupled to the CLK signal input. The gate of the NMOS transistor **818** is coupled to the CLKB signal input. The drains of the PMOS transistor **814**, the PMOS transistor **816**, and the NMOS transistor **806** are coupled to node C. The source of the NMOS transistor **820** is coupled to node SB.

FIG. 9 depicts an illustration of the HOLDB and SLEEPB signals in an exemplary embodiment of the invention.

The operation begins with CK going to zero. This causes CLKB to be equal to VDD and CLK to be equal to zero, which isolates the slave latch circuitry **530** from the master latch circuitry **510**. The HOLDB signal goes to 0 to retain the state of the slave latch. The SLEEPB signal then goes to -0.3V. This shuts off transistor M28 in FIG. 7A, which halts the leakage from all the circuits except in the slave latch circuitry **530**. When not in sleep mode, transistor M28 provides a low impedance path to ground.

The slave latch circuitry **530** is coupled to ground through the transistors M29 and M30, respectively depicted in FIGS. 7B and 7C. One purpose of transistor M29 is to provide a low impedance path to ground when not in sleep mode.

One purpose of transistor M30 is to provide a default moderate impedance path to ground when transistor M29 is off or in sleep mode. The leakage in the slave latch circuitry **530**, in going through transistor M30, causes node SB to rise. This provides a source bias to the slave NMOS transistors reducing the leakage through them and also reduces the voltage across the slave side to VDD-SB, which further reduces the leakage. Equilibrium is reached where the leakage cannot increase. Basically, the leakage is used to limit itself.

This embodiment uses the gated VDD solution because the voltage across the circuit is reduced to VDD-SB. This embodiment combines this gated VDD with the modulated back gate bias method because of the source bias SB but only for the NMOS transistors. This is accomplished without switching a lower VDD and driving a well. Thus, a simple process can be used. Also, this embodiment advantageously uses the moderate impedance transistor in a way that causes leakage to limit itself by reaching equilibrium.

FIGS. 10 and 11 disclose another embodiment for low leakage, data retention circuitry. In this embodiment, in a sleep state, the circuitries that do not require data retention are

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coupled to ground through a sleep transistor. The logic coupled to the transistors gated by the SLEEPB signal is shut off and draws minimal leakage. This process is accomplished by driving the SLEEPB signal below VSS by 0.3-0.4V. The HOLDB signal keeps the slave latch circuitry from changing state while the rest of the flip-flop comes out of the sleep state. The only part of the flip-flop still powered is the slave latch circuitry. The slave latch circuitry combines several techniques to minimize leakage.

FIG. 10 depicts circuitry **1000** for low leakage and data retention in an exemplary embodiment of the invention. The circuitry **1000** includes the inverter **1002**, the master latch circuitry **1010**, the slave latch circuitry **1020**, the inverter **1032**, the inverter **1034**, the sleep transistors **1042**, **1044**, **1046**, and **1048**, the inverter **1052**, and the inverter **1054**.

The D input is the input for the inverter **1002**. The master latch circuitry **1010** includes the transmission gate **1012**, the inverter **1014**, the transmission gate **1016**, and the inverter **1018**. The output of the inverter **1002** is coupled to the left contact of the transmission gate **1012**. The right contact of the transmission gate **1012** is coupled to the input of the inverter **1014** and the left contact of the transmission gate **1016**. The output of the inverter **1014** is coupled to the D input of the slave latch circuitry **1020** and the input of the inverter **1018**. The output of the inverter **1018** is coupled to the DB input of the slave latch circuitry **1020** and the right contact of the transmission gate **1016**.

The SLEEPB signal input is coupled to the gates for the SL1 sleep transistor **1042**, the SL2 sleep transistor **1044**, the SL3 sleep transistor **1046**, the SL4 sleep transistor **1048**, and the SLEEPB input of the slave latch circuitry **1020**. The SL1 sleep transistor **1042** is coupled to the inverter **1002** and ground. The SL2 sleep transistor **1044** is coupled to the inverter **1052**, the inverter **1054**, and ground. The SL3 sleep transistor **1046** is coupled to the inverter **1014**, the inverter **1018**, and ground. The SL4 sleep transistor **1048** is coupled to the inverter **1032**, the inverter **1034**, and ground. In some embodiments, the SL1 sleep transistor **1042**, the SL2 sleep transistor **1044**, the SL3 sleep transistor **1046**, and the SL4 sleep transistor **1048** can each be separated into two or more node each having its own NMOS sleep transistor.

The CK signal is the input of the inverter **1052**. The output of the inverter **1052** is coupled to the transmission gate **1012**, the transmission gate **1016**, and the input of the inverter **1054**. The output of the inverter **1054** is coupled to the transmission gate **1012**, the transmission gate **1016**, and the CLK input of the slave latch circuitry **1020**. The HOLDB signal input is coupled to the HOLDB input of the slave latch circuitry **1020**. The output of the slave latch circuitry **1020** is coupled to the input of the inverter **1032**. The output of the inverter **1032** is coupled to the input of the inverter **1034**. The output of the inverter **1034** is the Q signal.

FIG. 11 depicts slave latch circuitry **1020** in an exemplary embodiment of the invention. The slave latch circuitry **1020** includes D1 transistor **1102**, D2 transistor **1104**, DH transistor **1106**, DSL sleep transistor **1108**, stack transistors **1110**, stack transistors **1120**, D1B transistor **1132**, D2B transistor **1134**, DHB transistor **1136**, and sleep transistor **1138**.

The D1 transistor **1102**, the D2 transistor **1104**, the DH transistor **1106**, and the DSL sleep transistor **1108** are coupled to each other in series with the sleep transistor **1108** coupled to ground. The gate of the D1 transistor **1102** is coupled to the CLK signal input. The gate of the D2 transistor **1104** is coupled to the D signal input. The gate of the DH transistor **1106** is coupled to the HOLDB signal input. The gate of the sleep transistor **1108** is coupled to the SLEEPB signal input.

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The stack transistors **1110** comprise **P1** transistor **1112**, **P0** transistor **1114**, **N1** transistor **1116**, and **N0** transistor **1118**. The **P1** transistor **1112**, the **P0** transistor **1114**, the **N1** transistor **1116**, and the **N0** transistor **1118** are coupled to each other in series with the **N0** transistor **1118** coupled to ground. The gates of the **P1** transistor **1112**, the **P0** transistor **1114**, the **N1** transistor **1116**, and the **N0** transistor **1118** are coupled to the **LAT** signal input. The drains of the **P0B** transistor **1124** and the **N1B** transistor **1126** are coupled to the **LAT** signal input.

The stack transistors **1120** comprise **P1B** transistor **1122**, **P0B** transistor **1124**, **N1B** transistor **1126**, and **N0B** transistor **1128**. The **P1B** transistor **1122**, the **P0B** transistor **1124**, the **N1B** transistor **1126**, and the **N0B** transistor **1128** are coupled to each other in series with the **N0B** transistor **1128** coupled to ground. The gates of the **P1B** transistor **1122**, the **P0B** transistor **1124**, the **N1B** transistor **1126**, and the **N0B** transistor **1128** are coupled to the **LATB** signal input. The drains of the **P0** transistor **1114** and the **N1** transistor **1116** are coupled to the **LATB** signal input.

In operation, the logic coupled to the transistors gated by the **SLEEPB** signal is shut off and draws minimal leakage. This process is accomplished by driving the **SLEEPB** signal below **VSS** by 0.3-0.4V. The **HOLDB** signal keeps the slave latch circuitry **1020** from changing state while the rest of the flip-flop comes out of the sleep state. The only part of the flip-flop still powered is the slave latch circuitry **1020**. The slave latch circuitry **1020** combines several techniques to minimize leakage. Transistors not necessary for state retention (stacks with **CLK**) have sleep transistors to shut off leakage (gated by the **SLEEPB** signal).

The 8 transistors in the stack transistors **1110** and **1120** use two techniques to reduce leakage. The first technique used is transistor stacking, which is also called self-reverse bias. The **N0** transistor **1118** and the **N1** transistor **1116** will have some small leakage even when the gate is at 0V. As a result, **VNN1** will be at a positive voltage. This causes **VGS(N1)** and **VBS(N1)** to be negative, and **VDS(N1)** to decrease. Consequently, the leakage current is reduced in **N0** transistor **1118** and the **N1** transistor **1116**. The same effect occurs on **N0B** transistor **1128**, **N1B** transistor **1126**, **P0** transistor **1114**, **P1** transistor **1112**, **P0B** transistor **1124**, and **P1B** transistor **1122**.

The second technique is called multiple threshold transistors. Increasing channel length of MOS transistors increases the threshold of the devices without any change in process complexity. The **N0** transistor **1118**, the **N1** transistor **1116**, the **N0B** transistor **1128**, and the **N1B** transistor **1126** have increased channel length, which raises **VTH** and reduces leakage current.

This embodiment reduces leakage by a factor of 25 over a current standard cell D flip-flop. I/O Pad—FIG. 12

In some embodiments, a programmable general purpose input and output (I/O) padcell includes built in-level shifters and isolation that interface with the chip core logic. In these embodiments, a level shifter can be controlled to retain data.

FIG. 12 depicts circuitry **1200** for a level shifter for an I/O pad in an exemplary embodiment of the invention. The circuitry **1200** includes **MP2** transistor **1202**, **MP3** transistor **1204**, **M3** transistor **1206**, **M4** transistor **1208**, **M1** transistor **1210**, **M0** transistor **1212**, **M5** transistor **1214**, **M2** transistor **1216**, and an inverter **1218**.

The circuitry **1200** is for a latching level shifter. The **M3** transistor **1206** and the **M4** transistor **1208** are “native” cascode devices. The **M3** transistor **1206** and the **M4** transistor **1208** are also known as depletion-mode transistors. The **M3** transistor **1206** and the **M4** transistor **1208** are used to allow

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thin gate devices to be used in the input stage. This allows large voltage ratios between the **VDD** and the **V310**. The **M0** transistor **1212** and the **M1** transistor **1210** are output latching devices that allow the level shifter to retain the state when both **IN** and **INB** are 0. Thus, **IN** and **INB** control data retention.

In some embodiments, the gates of the **M3** transistor **1206** and the **M4** transistor **1208** are coupled to other transistors connected to the cascode voltage.

The following truth table is for circuitry **1200**.

IN	INB	OUT
0	0	Retain last state
0	1	0
1	0	1
1	1	Illegal

There will be setup time requirements for any signal compared to **SLPB**. If level shifters are used with an **SRAM** cell built into the output stage, the two inputs can be removed anytime after the output latch has flipped to a new state. Both 1.2V inputs to the level shifter cannot go to **VDD**. This can be prevented by including an inverter. If both the inverter and the level shifter have **SLPB** transistors, there is a potential timing race if **SLPB** goes to **VSS** with **VDD** high. In this case, the level shifters should be off before the output of the inverter drifts to **VDD**. In some embodiments, the **M5** transistor **1214** and the **M2** transistor **1216** can be configured to withstand greater voltages.

In some embodiments, the sources of the **M5** transistor **1214** and the **M2** transistor **1216** can be coupled to a common **SLEEPB** transistor **1240** to further reduce leakage. In one embodiment, the width of the **SLEEPB** transistor **1240** is 4 micrometers, and the length is 0.13 micrometers. The following truth table is for circuitry **1200** including this common **SLEEPB** transistor **1240**:

SLEEPB	IN	INB	OUT
1	0	0	Retain state (Data Retention)
1	0	1	0
1	1	0	1
1	1	1	Illegal
0	X	X	Retain State

In some embodiments, the **SLEEPB=0** input state should be understood to include the **SLEEPB** voltage being below 0V (E.g. -0.35V generated by a leakage optimization circuit).

In this extension to FIG. 12 (and the above truth table), the two Data Retention states may be operated independently, sequentially or simultaneously. This is beneficial when the **SLEEPB** input is used to control/limit leakage power while the **IN/INB=00** state is used for data retention. This is because the **SLEEPB** voltage comes from a charge pump and takes some time to transition from **Vdd (=1)** to the Data Retention mode.

The above description is illustrative and not restrictive. Many variations of the invention will become apparent to those of skill in the art upon review of this disclosure. The scope of the invention should, therefore, be determined not with reference to the above description, but instead should be

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determined with reference to the appended claims along with their full scope of equivalents.

While this invention has been particularly shown and described with references to example embodiments thereof, it will be understood by those skilled in the art that various changes in form and details may be made therein without departing from the scope of the invention encompassed by the appended claims.

What is claimed is:

1. A method carried out in an integrated circuit that includes an adaptive leakage controller, a power manager and a plurality of power islands, the method comprising:

receiving, at the power manager, a control signal from the adaptive leakage controller; and

employing the power manager to dynamically change power consumptions of the plurality of power islands, the employing the power manager to dynamically change power consumptions including: generating a variable voltage based on the control signal; and providing the variable voltage to at least one of low leakage sleep circuits of the integrated circuit.

2. The method as claimed in claim 1 further comprising putting to sleep and taking out of sleep, at different times, at least one of the power islands.

3. The method as claimed in claim 2 wherein the power manager employs a state machine to control the putting to sleep and the taking out of sleep.

4. The method as claimed in claim 1 wherein the variable voltage is an optimum voltage.

5. The method as claimed in claim 4 wherein the optimum voltage is dependent upon both process variation and temperature variation.

6. The method as claimed in claim 4 wherein the optimum voltage is generated by a sleep generator.

7. The method as claimed in claim 1 wherein the control signal is a digital signal.

8. The method as claimed in claim 1 wherein the at least one of the low leakage sleep circuits is connected in series to a source of a supply voltage and to a logic gate or storage cell of one of the power islands.

9. The method as claimed in claim 8 wherein the at least one of the low leakage sleep circuits modifies the supply voltage to the one of the power islands during a sleep mode.

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10. A method carried out in an integrated circuit that includes an adaptive leakage controller, a power manager, a plurality of power islands and a plurality of low leakage sleep circuits, the method comprising:

receiving, at the power manager, a control signal from the adaptive leakage controller; and

employing the power manager to dynamically change power consumptions of the plurality of power islands, the employing the power manager to dynamically change power consumptions including: generating a variable voltage based on the control signal; and providing the variable voltage to the plurality of low leakage sleep circuits,

wherein each of low leakage sleep circuits is associated with leakage reduction of a respective one of the plurality of power islands.

11. The method as claimed in claim 10 further comprising putting to sleep and taking out of sleep, at different times, at least one of the power islands.

12. The method as claimed in claim 11 wherein the power manager employs a state machine to control the putting to sleep and the taking out of sleep.

13. The method as claimed in claim 10 wherein the variable voltage is an optimum voltage.

14. The method as claimed in claim 13 wherein the optimum voltage is dependent upon both process variation and temperature variation.

15. The method as claimed in claim 13 wherein the optimum voltage is generated by a sleep generator.

16. The method as claimed in claim 10 wherein the control signal is a digital signal.

17. The method as claimed in claim 10 wherein at least one of the low leakage sleep circuits is connected in series to a source of a supply voltage and to a logic gate or storage cell of an associated one of the power islands.

18. The method as claimed in claim 17 wherein the at least one of the low leakage sleep circuits modifies the supply voltage to the associated one of the power islands during a sleep mode.

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